# **ECE 3040 Microelectronic Circuits**

Exam 1

February 15, 2017

24 minutes

Dr. W. Alan Doolittle

Print your name clearly and largely:

Solutions

#### **Instructions:**

Read all the problems carefully and thoroughly before you begin working. You are allowed to use 1 sheet of notes (1 page front and back) as well as a calculator. There are 100 total points. Observe the point value of each problem and allocate your time accordingly. SHOW ALL WORK AND CIRCLE YOUR FINAL ANSWER WITH THE PROPER UNITS INDICATED. *Write legibly. If I cannot read it, it will be considered a wrong answer.* Do all work on the paper provided. Turn in all scratch paper, even if it did not lead to an answer. *Turn in your notes sheet.* Report any and all ethics violations to the instructor. A periodic table is supplied on the last page. Good luck!

Sign your name on **ONE** of the two following cases:

I DID NOT observe any ethical violations during this exam:

I observed an ethical violation during this exam:

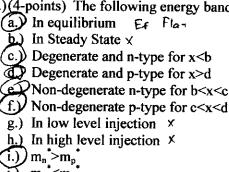
## First 33% Multiple Choice and True/False (Circle the letter of the most correct <u>answer or answers</u>)

- 1.) (3-points) True or False: The energy bandgap is generally larger in materials with strong chemical bonds.
- 2.) (3-points) True or False Metals are conductive because each atom prefers to not release its electrons to the electron cloud.
- 3.) (3-points) True or False? The density of states determines how likely the state is to be occupied
- 4.) (3-points) True of False: Al<sub>0.2</sub>In<sub>0.50</sub>Ga<sub>0.40</sub>N<sub>0.4</sub>P<sub>0.4</sub>As<sub>0.4</sub> is a valid semiconductor formula in standard semiconductor notation.
- 5.) (3-points) True or False: The fermi distribution function determines the probability of a hole existing in a state. 1 f(E)
- 6.) (3-points) True or False: In a degenerately doped semiconductor, one must use partial ionization. 7) (3-points) (True) or False: If a more guession: ether answer a cuepted
- 7.) (3-points) (True or False: If a material is non-degenerately doped, we know the fermi energy is located inside the bandgap and is at least 3kT away from either the conduction or valence band.

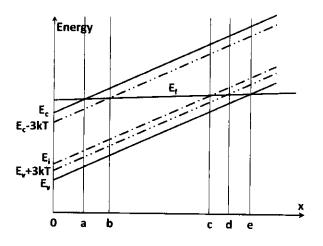
Select the **best** answer or answers for 8-10:

- 8.) (4-points) Which of the following are true about drift currents ...
  - a.) ... they only result from electric fields created by dopants  $\times$
  - b.)... they are driven by electric field
  - c.) ... they always result in diffusion currents that balance 🗴
  - d.) ... they are the smaller of the three types of current flow x
  - (e.) ... they are constant at high electric fields but vary linearly with electric field strength at low electric fields.
- 9.) (4-points) Which of the following are true about the fermi-distribution function.
  - (a.)) The product of the fermi-distribution function and the density of states results in a distribution of electron concentrations as a function of energy.
  - by The fermi-distribution function decays exponentially at higher energy
  - .)) The fermi-distribution function is always equal to ½ at energy equal to the fermi-energy
  - The fermi-distribution function reduces to a simple exponential for energies far away from the fermi-energy

#### 10.)(4-points) The following energy band diagram indicates the material is:



- j.)  $m_n < m_p$
- k Has zero electric field
- (1.) Has a non-zero electric field everywhere



Short Answer ("Plug and Chug"):

For the following problems (11-12) use the following material parameters and <u>assuming total</u> ionization:

For InP:

 $n_i=1.3e7 \text{ cm}^{-3}$  N<sub>D</sub>=1e17 cm<sup>-3</sup> donors N<sub>A</sub>=1.2e17 cm<sup>-3</sup> acceptors  $m_p^*=0.6m_o$   $m_n^*=0.08m_o$ E<sub>G</sub>=1.344 eV Electron mobility,  $\mu_n = 5000 \text{ cm}^2/\text{Vsec}$  Hole mobility,  $\mu_p = 150 \text{ cm}^2/\text{V-sec}$ Temperature=27 degrees C

11.)(5-points) Where is the fermi energy (relative to the valence band which is referenced to zero energy)?

12.) (8-points) A 12 nm (1 nm = 1e-9 m) <u>diameter</u> x 50 nm long cylindrical semiconductor resistor is made from the semiconductor from problem 11 for use in a microprocessor. It is biased on two opposing sides (longest dimension) with a 0.7 volt battery. Determine <u>both</u> the electron and hole <u>currents</u> flowing in the device.  $L = 5e^{-6}c^{-1}$ 

Area 
$$A = \pi (0.6 \times 10^{-6})^2$$
 Idami (D)  
= 1.13e-12 cm<sup>2</sup> 1.2x0<sup>-6</sup>cm  
 $P = \frac{1}{q(mn + Mpp)}$   $R = \frac{pL}{A}$   
 $l_n = \frac{1}{qun}$   $Pr^{-\frac{1}{qup}}$   
 $R = 1.47 e 17 Pr^{-\frac{1}{qup}}$   
 $R_n = 6.54 e 23 \Omega Rp = 9.21 e 6$   
 $I_n = 1e - 24 Amps$   $I p = 76 nA$ 

## Section 3 (more short answer)

- 13.)(14-points total) The material in problems 11 and 12 is exposed to the sun's light (like in a solar cell) that generates 1e19 cm<sup>-3</sup> extra electron - hole pairs.
  - a) (2 points) Is this low level or high level injection?

$$p = Dp + Po = le19 + 2e16$$
  
 $= le19 cm^{-3}$   
[High level injection]

b) (8 points) Draw the 1 dimensional energy band diagram showing the placement of both the quasi-fermi levels ( $E_{fn}$  and  $E_{fp}$  – should be a numeric answer) relative to  $E_i$ ,  $E_c$ , and  $E_v$ .

$$F_{n} = h = h = e^{(F_{n} - F_{i})/47} \qquad F_{n} \qquad F_{n} \qquad F_{n} = \frac{1.4 \, \lambda e^{V}}{1.4 \, e^{V}} \qquad F_{n} = \frac{1.4 \, \lambda e^{V}}{1.344} \qquad F_{n} = \frac{1.344}{1.344} \qquad F_{n} = \frac{10.711}{1.00 \, 2e^{19} \, cm^{-3}} \qquad F$$

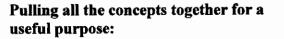
c) (4 - points) What is the total current flowing when light is present?

`\*...

(s) What is the total current flowing when light is present?  

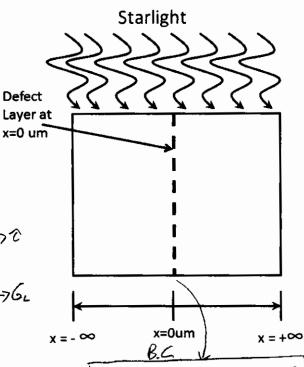
$$\begin{aligned}
R &= \frac{\ell L}{A} \\
R &= \frac{\ell L}{A} \\
R &= 537 \ R \\
\end{bmatrix}$$

$$= 1.6e - 19 (5000 \times 1e19 + 150 \times 1e19) \qquad R = 537 \ R \\
\end{bmatrix}$$



### 14.) (40-points)

An infinite slab of semiconductor extends from positive to negative infinity. For a very long time, starlight illuminated constantly the has absorbed semiconductor and is uniformly with a very small absorption The semiconductor is coefficient. doped p-type with an acceptor concentration of 5e15 cm<sup>-3</sup> and has a carrier lifetime of (2)minority microseconds. The sunlight is absorbed the semiconductor uniformly in generating an excess minority carrier concentration rate of 10<sup>14</sup> cm<sup>-3</sup>/sec. At the center of the semiconductor at x=0, a defect layer exists which results in a minority carrier lower excess



concentration than anywhere else in the semiconductor. Thus, at x=0,  $\Delta n(x=0)=1e8$  cm<sup>-3</sup>. If the semiconductor is held at room temperature (27 degrees C), determine the minority carrier diffusion current density at all positions in the semiconductor ( $-\infty \ge x \ge \infty$ ). Assume a minority carrier mobility of 2 cm<sup>2</sup>/Vsec) and the intrinsic concentration is 1e-14cm<sup>-3</sup>.

Hint: It may be neight to break tins problem up into two symmetric problems.  

$$L_{n} = \sqrt{D_{n}c} = \sqrt{Q_{n}O_{5} + 8(2e^{-c})} = 3, 2|q \ \text{m} \qquad D_{n} = \frac{kT}{q_{p}} = 0, 05 + 8c^{-2}/sec$$
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}} - \frac{\Delta n_{p}}{\tau_{n}}$  General Solution is:  $\Delta n_{p}(x) = Ae^{-\frac{1}{2}L_{n}} + Be^{+\frac{1}{2}L_{n}}$   
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}} - \frac{\Delta n_{p}}{\tau_{n}} + G_{L}$  General Solution is:  $\Delta n_{p}(x) = Ae^{-\frac{1}{2}L_{n}} + Be^{+\frac{1}{2}L_{n}} + G_{L}\tau_{n}$   
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}}$  General Solution is:  $\Delta n_{p}(x) = Ae^{-\frac{1}{2}L_{n}} + Be^{+\frac{1}{2}L_{n}} + G_{L}\tau_{n}$   
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}}$  General Solution is:  $\Delta n_{p}(x) = A + Bx$   
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}} + G_{L}$  General Solution is:  $\Delta n_{p}(x) = Ax^{2} + Bx + C$   
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}} + G_{LO}f(x)$  General Solution is:  $\Delta n_{p}(x) = \int_{0}^{2} \frac{G_{LO}f(x)}{D_{N}} \int_{0}^{2} f(x) dx^{2} + Bx + C$   
Given:  $0 = D_{n} \frac{d^{2}\Delta n_{p}}{dx^{2}} + G_{LO}f(x)$  General Solution is:  $\Delta n_{p}(x) = \left[-\frac{G_{LO}}{D_{N}}\int_{0}^{2} f(x) dx^{2}\right] + Bx + C$   
Given:  $\frac{d\Delta n_{p}}{L} = -\frac{\Delta n_{p}}{L}$  General Solution is:  $\Delta n_{p}(t) = \Delta n_{p}(t = 0)e^{-\frac{1}{2}T_{n}}$ 

Extra work can be done here, but clearly indicate which problem you are solving.

$$\frac{U_{52}}{W_{52}} = \frac{1}{2} \sum_{x=0}^{\infty} \frac{1}$$

Extra work can be done here, but clearly indicate which problem you are solving.

